

Title (en)

METHOD FOR EXAMINING THE PRODUCTION QUALITY OF AN OPTICAL SECURITY FEATURE OF A VALUABLE DOCUMENT

Title (de)

VERFAHREN ZUM PRÜFEN DER HERSTELLUNGSQUALITÄT EINES OPTISCHEN SICHERHEITSMERKMALS EINES WERTDOKUMENTS

Title (fr)

PROCÉDÉ DE CONTRÔLE DE LA QUALITÉ DE FABRICATION D'UNE CARACTÉRISTIQUE DE SÉCURITÉ D'UN DOCUMENT DE VALEUR

Publication

**EP 2761604 B1 20210324 (DE)**

Application

**EP 12773214 A 20120925**

Priority

- DE 102011114410 A 20110926
- EP 2012004011 W 20120925

Abstract (en)

[origin: WO2013045074A1] The invention relates to a method for examining the production quality, preferably the printing quality, of a predefined optical security feature in or on a predefined section of a valuable document, on the basis of pixel data of pixels of an image of said predefined section, wherein these data are associated, in each case, with locations in or on said section and reproduce optical characteristics of the valuable document at those locations. In this method, an examination takes place as to whether a first count, or a first portion, of those pixels of the image pixels with pixel data lying, according to a first predefined criterion, within a predefined first reference range for the security feature, exceeds a predefined first target minimum value for said security feature, and whether a first dispersion of the pixel data of those pixels lying, according to said first criterion, within the first reference range for the pixel data, exceeds a predefined first minimum dispersion for the security feature. Depending on the result of this examination, a quality signal is generated which only indicates that the printing quality is sufficient if the first count or the first portion exceeds the first target minimum value and the dispersion exceeds the first minimum dispersion.

IPC 8 full level

**G07D 7/202** (2016.01); **G07D 7/00** (2016.01); **G07D 7/12** (2016.01)

CPC (source: EP US)

**G07D 7/003** (2017.04 - EP US); **G07D 7/0032** (2017.04 - EP); **G07D 7/12** (2013.01 - EP US); **G07D 7/2041** (2013.01 - EP US)

Citation (examination)

- US 2005100204 A1 20050512 - AFZAL ROBERT S [US], et al
- EP 1990779 A2 20081112 - SUISSE ELECTRONIQUE MICROTECH [CH]

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

DOCDB simple family (publication)

**DE 102011114410 A1 20130328**; CN 103827929 A 20140528; CN 103827929 B 20170609; EP 2761604 A1 20140806; EP 2761604 B1 20210324; US 2014233829 A1 20140821; US 9202327 B2 20151201; WO 2013045074 A1 20130404

DOCDB simple family (application)

**DE 102011114410 A 20110926**; CN 201280046851 A 20120925; EP 12773214 A 20120925; EP 2012004011 W 20120925; US 201214347308 A 20120925